Low dielectric loss ceramics in the Mg₄Nb₂O₉-ZnAl₂O₄-TiO₂ ternary system Yu-Chuan Wu¹, Hsiao-Ting Tseng², Chi-Shiung Hsi², Jari Juuti ³, Hsing-I Hsiang^{4, *} ¹ Department of Materials and Mineral Resources Engineering, National Taipei University of Technology, Taipei, Taiwan

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Abstract

This study used a traditional solid-state reaction method to prepare a series of composite ceramics in the $0.7Mg_4Nb_2O_9$ - $(0.3-x)ZnAl_2O_4$ - $xTiO_2$ ternary system. Crystalline phases and microstructure of $Mg_4Nb_2O_9$ - $ZnAl_2O_4$ - TiO_2 dielectric ceramic composites were investigated and correlated with the relevant dielectric properties. It was observed that the addition of Ti^{4+} substituted Nb^{5+} in the $Mg_4Nb_2O_9$ structure, which promoted the decomposition of $Mg_4Nb_2O_9$ to form the second phase, $Mg_5Nb_4O_{15}$, during sintering. The synergistic effect of $ZnAl_2O_4$ - TiO_2 co-doping promoted the $Mg_4Nb_2O_9$

ceramic densification. The sample $(0.7Mg_4Nb_2O_9-(0.3-x)ZnAl_2O_4-xTiO_2)$ with x = 0.15-0.2 exhibited dielectric constants of 13-14, larger than those of ZnAl_2O_4, Mg_4Nb_2O_9 and Mg_5Nb_4O_{15}, due to the NbO_6 octahedra distortion resulting from the substitution of Al³⁺/Ti⁴⁺ for Nb⁵⁺ in Mg_4Nb_2O_9 and Mg_5Nb_4O_{15}. The long-range order of the NbO₆ octahedra was enhanced by co-doping ZnAl_2O_4 and TiO_2, thereby enhancing the Qxf value. A dielectric constant of 13.1, Qxf value of 366,000 GHz and a τ_f of -60.8ppm/°C were obtained from 1300°C sintered 0.7Mg_4Nb_2O_9-0.15ZnAl_2O_4-0.15TiO_2 ceramic is a good candidate for microwave electronic device applications.

Keywords: dielectric loss, Mg₄Nb₂O₉, ZnAl₂O₄, TiO₂, microwave ceramics

1. Introduction

Low-permittivity dielectric ceramics are used for millimeter-wave communication and as microwave ceramic substrates. As the permittivity decreases, the signal transmission speed increases. Dielectric ceramics with properties of temperature-stability, low-permittivity and a high Qxf are required in millimeter-wave applications. High Qxf dielectric ceramics minimize circuit insertion losses and can be used for highly selective filters. Searching for new microwave dielectric ceramics with high-temperature stability, low permittivity, high Qxf and low cost has always attracted much attention [1-3]. The microwave dielectric properties of ceramics are determined by several parameters, including the phase composition, the processing conditions and their ultimate densification/porosity [4]. One effective method for obtaining a lower temperature-sintered microwave dielectric ceramic with high Qxf and near-zero τ_f values is by adding low-temperature-fired ceramics to the dielectric [5-6].

Ogawa et al. [7] first reported the microwave dielectric properties ($\varepsilon_r = 12.4$, Qxf ~ 19,400 GHz, $\tau_f = -70$ ppm/°C) of Mg₄Nb₂O₉ ceramics sintered at 1400°C for 10 h. Mg₄Nb₂O₉ ceramic exhibits an ordered corundum structure in which the NbO₆ octahedral layer along the c axis is separated by the MgO₆ octahedral layer and the cation vacancy layer. In contrast, the NbO₆ octahedral layer along the b axis is sandwiched by two MgO₆ octahedral layers [8]. Mg₄Nb₂O₉ ceramics have gained much attention due to their high Qxf and low ε_r value [9-11]. However, the drawbacks of Mg₄Nb₂O₉ ceramics, such as a higher sintering temperature and a significant negative τ_f , adversely affect their application. The addition of TiO₂ with positive τ_f to Mg₄Nb₂O₉ ceramics has been used to improve the τ_f [12].

ZnAl₂O₄ ceramic exhibiting a spinel structure has been considered a potential microwave ceramic substrate material [13-15]. Surendran et al. first reported the microwave dielectric properties ($\varepsilon_r = 8.5$, Qxf ~ 56,300 GHz, $\tau_f = -79$ ppm/°C) of ZnAl₂O₄ ceramic [13]. Zheng et al. [14] reported that good dielectric properties ($\varepsilon_r = 8.56$, Qxf = 106,000 GHz and $\tau_f = -63$ ppm/°C) can be obtained for 1650°C sintered

ZnAl₂O₄ ceramic. The Q×f of ZnAl₂O₄ ceramic sintered at 1600°C was enhanced by forming a (Zn_{1-x}Mg_x)Al₂O₄ solid solution which reached above 140,000 GHz [15]. The addition of 2 wt% TiO₂ promoted the densification and dielectric properties of Zn_{0.9}Mg_{0.1}Al₂O₄ sintered at 1500°C ($\varepsilon_r = 8.57$, Qxf ~ 180,800 GHz, $\tau_f = -41.5$ ppm/°C) [16].

Due to crystal structure differences, Mg₄Nb₂O₉, ZnAl₂O₄ and TiO₂ cannot form a solid solution, instead forming ceramic matrix composites with adjustable dielectric properties. The proper addition of $ZnAl_2O_4$ and TiO_2 may promote the densification. improve the quality factor and compensate the temperature coefficient (τ_f) of Mg₄Nb₂O₉ ceramics. To our knowledge, there are very few reported investigations into the behaviour of the Mg₄Nb₂O₉- ZnAl₂O₄-TiO₂ composites which might exhibit promising features for microwave dielectric ceramics. In a previous study, the $xMg_4Nb_2O_9-(1-x)/2ZnAl_2O_4-(1-x)/2TiO_2$ (x = 0.4-0.8) ternary system with quality factors between 10,500 and 120,000 was investigated [17]. This study designed and prepared a series of composite ceramics in the 0.7Mg₄Nb₂O₉-(0.3-x)ZnAl₂O₄-xTiO₂ ternary system via a traditional solid-state reaction method. Crystalline phases and microstructure of Mg₄Nb₂O₉-ZnAl₂O₄-TiO₂ dielectric ceramic composites were investigated and correlated with the relevant dielectric properties.

2. Experimental procedure

According to the stoichiometric ratio of Mg₄Nb₂O₉ and ZnAl₂O₄, barium niobate and zinc aluminate powders were prepared via the mixed oxides process with reagent-grade MgO, Nb₂O₅, ZnO and Al₂O₃. The calcination conditions of Mg₄Nb₂O₉ powder were held at a temperature of 1300°C for 3h. The ZnAl₂O₄ powder was calcined at 1200°C for 2h. The 0.7Mg₄Nb₂O₉-yZnAl₂O₄-xTiO₂ ternary systems; (MZ015: x = 0, y=0.15), (MZT015: x = 0.15, y=0.15), (MZT175: x = 0.175, y=0.125), (MZT020: x = 0.2, y=0.1) and (MT015: x = 0.15, y=0) were prepared from mixtures of reagent-grade TiO₂, Mg₄Nb₂O₉ and ZnAl₂O₄ powders, and the mixed powders were then milled for 3 h using Y-TZP balls. The milled powders were dried in an oven and PVA was then added for granulation. The powders were uniaxially pressed at 255 MPa into disks of 10 mm diameter and 5 mm thickness. These pressed disks were debinded at 450°C for 1 h and sintered at 1250°C - 1500°C for 3 h.

The crystalline phases of sintered pellets were determined by X-ray diffractometry (Brucker, D2 Phaser, Cu-K α radiation, Karisruhe, Germany). The relative fractions of the constituent phases were quantitatively analyzed from the XRD data using Bruker Topas v4.2 software. The relative densities were calculated from the ratios of apparent density and true density of the sintered disks. Archimedes' method was used to measure the apparent densities of the sintered samples. The sintered disks

were ground into powder and the true densities of the ground powders were measured using helium pycnometry (Quantachrome, ULTRAPYC 1200e, Boynton Beach, FL, USA). Scanning electron microscopy (JEOL JSM-5600F, Tokyo, Japan), transmission electron microscopy (JEOL, JSM-2100F, Tokyo, Japan) and energy dispersive spectroscopy (EDS, Oxford Instruments, 6587, High Wycombe, UK) were used to observe the sintered pellets' microstructure, crystalline phase and chemical composition. For SEM analysis, the surface of the ceramics was ground using SiC 1200 grit paper and polished using diamond paste. The polished samples were then thermally etched at 1200°C for 5 min in air. Thin foils for TEM observation were prepared via the conventional technique: the sintered disks were sliced to a thickness of $\sim 200 \ \mu m$ and then mechanically polished to a thickness of $\sim 30 \ \mu m$ followed by ion-beam thinning to electron transparency. Raman spectra were measured by a Raman spectrometer (Dong Woo 500i, Gyeonggi-do, South Korea) with conditions of a detecting time of 50 s and resolution of 1 cm⁻¹. Samples were excited by an Ar ion laser beam with a wavelength of 532 nm and power output of 35 mW.

The relative permittivity (ϵ_r) and quality factor (Q) at microwave frequency were measured with the Hakki-Coleman dielectric resonator method using a HP8757D (Agilent Technologies, Palo Alto, CA) network analyzer and a HP8350B (Agilent Technologies) sweep oscillator. The Q value was measured using the TE011 resonant peak and τ_f was obtained by measuring the resonant frequency in the temperature range of 25–85°C. The τ_f value (ppm/°C) was calculated by noting the change in resonant frequency.

3. Results and discussion

Figure 1 shows the XRD patterns of the MZT015 sintered at various temperatures. All the samples had a well-defined main phase; Mg₄Nb₂O₂ a minor phase of ZnAl₂O₄ and an evident second phase of Mg5Nb4O15 were observed. The diffraction peak of the TiO2 phase was not observed in the XRD profiles. Su et al. [12], who reported that the Mg₅Nb₄O₁₅ phase formed after sintering of Mg₄Nb₂O₉ with TiO₂ as an additive, also observed consistent results. The diffraction angles of Mg4Nb2O9 and Mg5Nb4O15 phases shifted to higher values as the sintering temperature increased. This suggested that the unit cell volumes of Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅ decreased with increasing sintering temperature [18-19]. Table S1 (supplementary materials) shows the lattice parameters of the MZT015 sintered at various temperatures. The lattice parameters of Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅ decreased with increasing sintering temperature due to the increase in the ion substitution of Ti^{4+} (ionic radius = 0.60 nm) for Nb⁵⁺ (ionic radius = 0.61 nm) [20]. Table S2 (supplementary materials) shows the phase content of the samples sintered at 1300°C. As the TiO₂ content increased from 15 mol% to 20 mol%, the content of the Mg₅Nb₄O₁₅ phase increased from 32.2 wt% to 41.3 wt% in the $0.7Mg_4Nb_2O_9$ - $(0.3-x)ZnAl_2O_4$ - $xTiO_2$ ternary system, while the content of the ZnAl_2O_4 phase remained almost unchanged (at about 5 wt%). The amounts of the Mg₅Nb₄O₁₅ phase in MZ015 and MT015 were 12.7 wt% and 45.5 wt%, respectively. The phase diagram of Nb₂O₅-MgO predicts that the Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅ coexist at equilibrium because the molar ratio of Nb₂O₅ to MgO is slightly larger than 20/80 [21]. These results suggest that the addition of Ti⁴⁺ dissolved in Mg₄Nb₂O₉ mainly replaced Nb⁵⁺, which thus promoted the decomposition of Mg₄Nb₂O₉ and formed the second phase of Mg₅Nb₄O₁₅ [12].

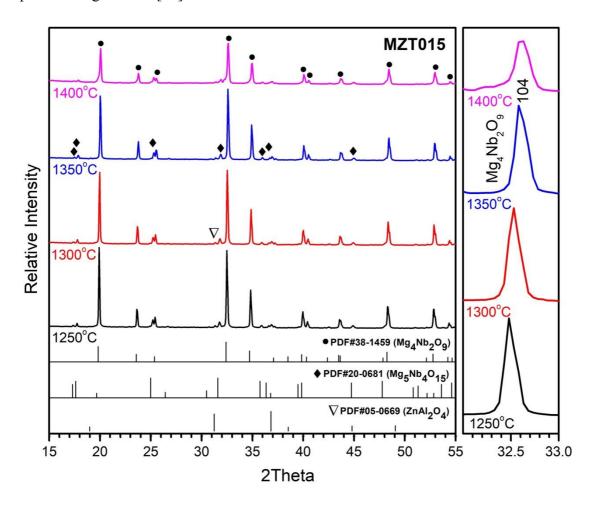
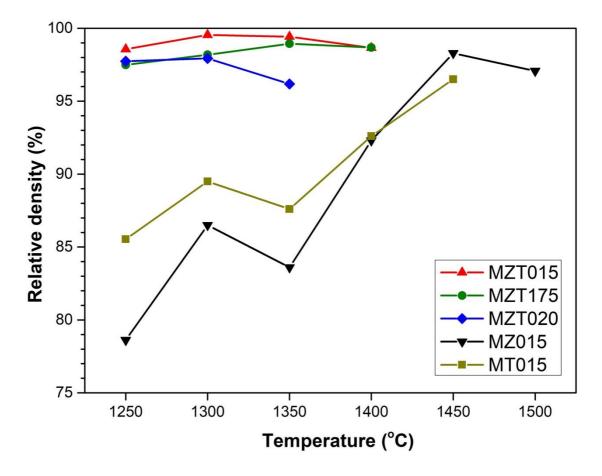


Fig. 1 XRD patterns of the MZT015 dielectric ceramics sintered at various temperatures.

Figure 2 shows the relative densities of the samples sintered at various temperatures. For the MZ015 and MT015 sintered disks, the relative densities were not greater than 90% until the sintering temperature reached 1400°C. The samples in the 0.7Mg₄Nb₂O₉-(0.3-x)ZnAl₂O₄-xTiO₂ ternary system initially had relative densities higher than 95%. These increased slightly with increasing sintering temperature and reached a maximum value in the sintering temperature range from 1300°C to 1350°C. Based on the system of Nb₂O₅-MgO, the liquidus temperature decreases when increasing the molar ratio of Nb₂O₅ to MgO in the coexistence region of Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅ [21]. The addition of Ti^{4+} substituting Nb⁵⁺ in the Mg₄Nb₂O₉ structure made the sintered samples become Nb-excess and decreased the liquidus temperature. The addition of Ti⁴⁺ reduced the liquidus temperature, which reduced the activation energy of sintering and high sinterability at a low temperature [22]. Huang et al. [23] developed low-loss microwave dielectrics using (Mg_{1-x}Zn_x)₄Nb₂O₉ solid solution; they concluded that the addition of Zn^{2+} decreased the densification temperature of $(Mg_{1-x}Zn_x)_4Nb_2O9$ dielectric from 1400°C to 1340°C. The synergistic effect of the ZnAl₂O₄-TiO₂ codoping enhancing the densification of Mg₄Nb₂O₉ ceramics was observed in this study.

At a sintering temperature of 1300°C, the MZT015 sample exhibited the highest



relative densities compared with other compositions.

Figure 2 Relative densities of the 0.7Mg₄Nb₂O₉-yZnAl₂O₄-xTiO₂ ternary dielectrics sintered at various temperatures.

The SEM micrographics of the MZT015 sintered at various temperatures and MZT175 sintered at 1400°C are shown in Figure 3. All samples exhibited a dense microstructure, which is consistent with the relative sintered density results. The incidence of large and elongated matrix grains was increased by increasing the sintering temperature. The MTZ015 sample sintered at 1250°C for 3 h had a grain size around 5 µm, as shown in Fig 3(a). When the sample was sintered at 1350°C for 3 h, the grains in the sintered pellet became elongated with dimensions larger than 10 μ m, as indicated in Fig 3(c). The MTZ175 sintered at 1400°C for 3 h had a matrix grain size larger than 15 µm, as shown in Fig 3(d). Precipitates with small grain size located inside the grains as intragranular precipitates, and also at the grain boundaries or triple junctions, were observed. The EDS analysis results obtained from the regions marked A, B and C in Fig. 3(d) are tabulated in Table S3 (supplementary materials). The (Mg+Zn) to (Nb+Al+Ti) molar ratio of large matrix grains was 2.1, corresponding to the composition of Mg₄Nb₂O₉. The intragranular precipitate, point B in Fig 3(d), had an (Mg+Zn) to (Nb+Al+Ti) molar ratio of 1.18 and was compatible with the composition of Mg₅Nb₄O₁₅. The grain located at the triple junction, as indicated by the arrow in Fig. 3(d), had an (Mg+Zn) to (Nb+Al+Ti) molar ratio of 0.56. It had a very low Nb⁵⁺ content, which was considered as a (Mg/Zn)Al₂O₄ solid solution based on the XRD analysis results (Figure 1). The Mg₅Nb₄O₁₅ and ZnAl₂O₄ phases existed in the 1300°C sintered MZT015 sample and can also be identified by the HRTEM images, diffraction patterns and the corresponding fast Fourier transform (FFT) patterns (Fig. S1, supplementary materials).

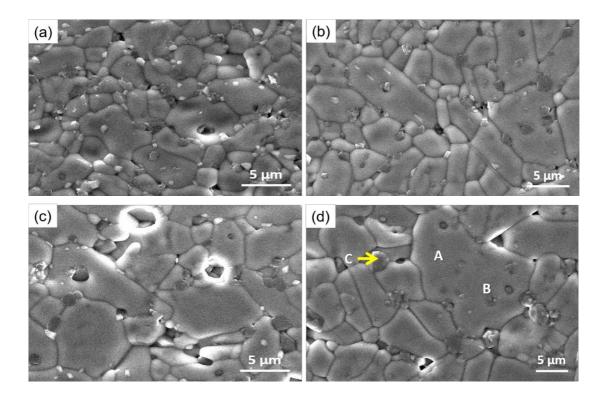


Fig. 3 SEM microstructures of the MZT015 sintered at various temperatures (a)

1250°C, (b)1300°C, (c) 1350°C, and (d) MZT175 sintered at 1400°C.

The previous paragraph suggests that a large proportion of Al^{3+} in the ZnAl₂O₄ and Ti⁴⁺ in the TiO₂ diffused into the Mg₄Nb₂O₉ lattice and a large proportion of Mg²⁺ migrated into the ZnAl₂O₄ from the Mg₄Nb₂O₉. As the chemical composition of Mg₄Nb₂O₉ changes from stoichiometric to Nb-rich phase, the single Mg₄Nb₂O₉ phase becomes the mixture phases of Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅[21]. Bezjak et al. [24] investigated the synthesis and polymorphic phase transition of Ba₄Nb₂O₉ and observed that wellcrystallized hexagonal Ba₄Nb₂O₉ grains tended to decompose into BaO-rich amorphous phase and nanocrystalline Ba₅Nb₄O₁₅ during sintering. They inferred that the substitution of Al³⁺ and Ti⁴⁺ for Nb⁵⁺ in Mg₄Nb₂O₉ may promote the decomposition of $Mg_4Nb_2O_9$ into $Mg_5Nb_4O_{15}$ and that the MgO-rich amorphous phase easily reacts with $ZnAl_2O_4$ and forms (Mg/Zn)Al_2O_4 solid solution.

The Raman spectra of Mg₄Nb₂O₉ and MZT015 sintered samples are displayed in Fig. 4. Strong Raman active modes were observed at 330 cm⁻¹, 380 cm⁻¹, and 810 cm⁻¹, which were assigned to the symmetric bending modes (F2g mode) and stretching modes (A_{1g} mode) of NbO₆ octahedra with Oh symmetry, respectively [25]. The significant distortion of NbO₆ octahedra resulted in the Raman peak broadening or splitting. At about 810 $\text{cm}^{-1},\,A_{1g}\,\text{mode},$ the strongest band was ascribed to the shortest Nb-O bond length. Sample MZT015 displayed the A_{1g} mode split into three Raman-active modes. This was attributed to the presence of different Nb-O bond distances resulting from the coexistence of Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅. In addition, a higher wave number of the A_{1g} mode in MZT015 (818 cm⁻¹) was observed compared with Mg₄Nb₂O₉ (812 cm⁻¹). This was due to the decrease in the oxygen octahedron size [26] resulting from the Ti⁴⁺ substituting Nb⁵⁺. The F_{2g} mode is associated with the internal vibrations of an oxygen octahedron. Figure 4 shows the F_{2g} mode split into a doublet at 330 and 380 cm⁻¹ due to the empty octahedra resulting from a slight local departure from the $P\overline{3}c1$ space group [27]. This was expected to be split due to the distortion of NbO₆ octahedra for MZT015. Phonons of MZT015 and Mg₄Nb₂O₉ exhibited nearly the same peak position of the F_{2g} mode; this was because the F_{2g} mode was not affected by the slight lattice

distortions reported by Siny et al. [28]. The F_{2g} mode is only sensitive to long-range order on the NbO₆ octahedra, while the A_{1g} mode is caused by either long-range or short-range order [29]. The narrower band width and higher intensity of the F_{2g} mode are characteristic of the enhanced level of ordering. MZT015 exhibited higher intensities and a narrower peak width of the F_{2g} mode than $Mg_4Nb_2O_9$, suggesting that long-range order was enhanced for sample MZT015. This may be due to the aliovalent Al^{3+}/Ti^{4+} cations and Nb⁵⁺ that tend to occupy specific NbO₆ octahedron sites to decrease the lattice strain, resulting in an ordered crystal structure [28].

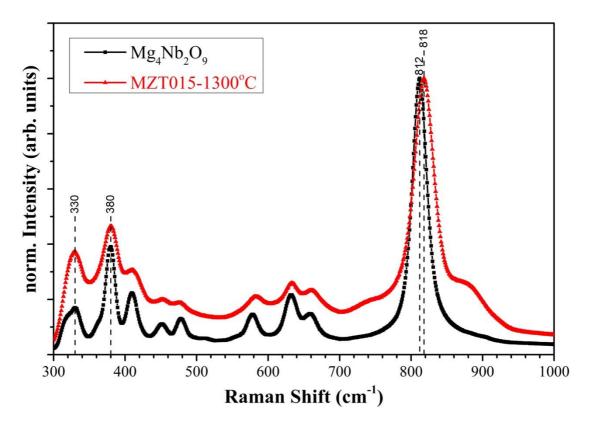


Fig.4 Raman spectra of Mg₄Nb₂O₉ and MZT015 sintered at 1300°C.

Table I shows the variation of the dielectric properties of the samples with different sintering temperatures. The dielectric properties of Mg₄Nb₂O₉, Mg₅Nb₄O₁₅, ZnAl₂O₄

and TiO₂ reported in the literature are tabulated in Table II. It is well known that the relative density and phase constituent determine the dielectric constant. The dielectric constant of the sample MZ015, without the addition of TiO₂ ($\varepsilon_r = 105$), was 12.8, which was the lowest among these samples owing to the highest number of pores ($\varepsilon_r = 1$). As listed in Table II, the dielectric constants of Mg₄Nb₂O₉, Mg₅Nb₄O₁₅, ZnAl₂O₄ and MgAl₂O₄ phases are all lower than 13. The MZT sample (0.7 Mg₄Nb₂O₉-(0.3-x) $ZnAl_2O_4$ -xTiO₂) with x = 0.15-0.2 and the MT015 samples exhibited dielectric constants between 13 and 14. This is due to the larger NbO₆ octahedra distortion [27] resulting from the substitution of Al^{3+}/Ti^{4+} for Nb^{5+} in $Mg_4Nb_2O_9$ and $Mg_5Nb_4O_{15}$, thereby resulting in a higher dielectric constant. The Qxf value is dependent on the relative density, constituent phase and the ordering of cations in NbO₆ octahedra [4]. The Qxf value of the samples increased with increasing sintering temperature and reached a maximum value, then declined, which showed a similar trend to that of the relative density behaviour. The maximum Qxf value for the MZT015, MZT175 and MZT020 samples were 366,000, 296,000 and 176,000, respectively. The maximum Qxf value decreased with the increase of the TiO₂ addition, which was due to the amount of the second phase, Mg₅Nb₄O₁₅, which increased with increasing TiO₂ addition.

Table I Dielectric properties of the samples sintered at different temperatures.

MZT015	MZT175	MZT020	MT015	MZ015
MZ1015	MZ11/5	MZ1020	M1015	MZ015

Sintering											
Temperature	ε _r	Qxf*	$\tau_{f}^{\;+}$	ε _r	Qxf	٤ _r	Qxf	ε _r	Qxf	ε _r	Qxf
(°C)											
1250	13.6	208k	-	13.6	230k	13.8	147k	-	-	-	-
1300	13.1	366k	-60.8	13.7	296k	13.6	66k	-	-	-	-
1350	13.1	325k	-62.3	13.5	274k	13.2	32k	-	-	-	-
1400	13.2	341k	-64.3	13.2	122k	-	-	13.0	16.2k	12.8	13.7k

*unit of Qxf: GHz, +unit of $\tau_{f. ppm/^{\circ}C}$

Table II Dielectric properties of Mg₄Nb₂O₉, ZnAl₂O₄, TiO₂, Mg₅Nb₄O₁₅, and

Materials	٤r	Q×f(GHz)	τ _f (ppm/°C)	ref
Mg ₄ Nb ₂ O ₉	12.4	192268	-70.5	Yoshida [9]
ZnAl ₂ O ₄	8.5	56300	-79	Huang [15]
TiO ₂	105	17600	411	Surendran [13]
Mg5Nb4O15	11.3	43300	-58	Wu [30]
MgAl ₂ O ₄	8.75	68900	-75	Surendran [31]

MgAl₂O₄ reported in the literature

Since the $Mg_4Nb_2O_9$ phase exhibited a higher Qxf value than the $Mg_5Nb_4O_{15}$, the presence of the second phase, $Mg_5Nb_4O_{15}$, degraded the Qxf value of the samples. The MZT015 and MZT175 sintered disks exhibited higher Qxf values than those of the end

members. The ordering of cations in NbO₆ octahedra has been shown to dominate the Qxf value [32]. The substitution of aliovalent Al³⁺/Ti⁴⁺ for Nb⁵⁺ enhanced the longrange order of NbO₆ octahedra for MZT015 and MZT175, which had a significantly beneficial effect on Qxf values. Huang et al. [23] reported that the substitution of Zn²⁺ for Mg²⁺ in Mg₄Nb₂O₉ can also substantially increase the Q×f value. Moreover, the Q×f value of ZnAl₂O₄ ceramic could be significantly improved by forming a (Zn₁xMg_x)Al₂O₄ solid solution [15]. Therefore, a low dielectric loss Mg₄Nb₂O₉ ceramic can be obtained by co-doping the proper amount of ZnAl₂O₄ and TiO₂. The $\tau_{\rm f}$ is mainly determined by the relative sintered density and the constituent phase. For MZT015, the $\tau_{\rm f}$ was about -60 ppm/°C and almost independent of the sintering temperature due to there being no significant constituent phase change. It is difficult to adjust the $\tau_{\rm f}$ to zero due to the chemical reaction between TiO₂ and Mg₄Nb₂O₉ during sintering.

4. Conclusions

The development of crystalline phases and microstructures of $Mg_4Nb_2O_9$ -ZnAl₂O₄-TiO₂ dielectric ceramics with different phase compositions after sintering has been investigated. The substitution of Al³⁺ and Ti⁴⁺ for Nb⁵⁺ in Mg₄Nb₂O₉ may promote the decomposition of Mg₄Nb₂O₉ into Mg₅Nb₄O₁₅. The addition of Ti⁴⁺ dissolved in Mg₄Nb₂O₉ mainly substituted Nb⁵⁺, which led to the chemical composition becoming Nb-excess. This in turn resulted in a decrease in the liquidus temperature and promotion of the densification. The long-range order on the NbO₆ octahedra was enhanced by the co-doping of ZnAl₂O₄ and TiO₂ to Mg₄Nb₂O₉, thereby increasing the Q×f value. The sample (0.7Mg₄Nb₂O₉-(0.3-x)ZnAl₂O₄-xTiO₂) with x = 0.15-0.2 exhibited a dielectric constant of 13-14, larger than ZnAl₂O₄, Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅. This was due to the larger NbO₆ octahedra distortion resulting from the substitution of Al³⁺/Ti⁴⁺ for Nb⁵⁺ in Mg₄Nb₂O₉ and Mg₅Nb₄O₁₅. A dielectric constant of 13.1, a high Qxf value of 366,000 GHz and a $\tau_{\rm f}$ of -60.8ppm/°C can be obtained for 0.7Mg₄Nb₂O₉-0.15 ZnAl₂O₄-0.15TiO₂ sintered at 1300°C.

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